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### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### Applications of Embedded - CPLDs

#### Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	16
Number of Macrocells	256
Number of Gates	5000
Number of I/O	164
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP Exposed Pad
Supplier Device Package	208-RQFP (28x28)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/epm7256src208-15n">https://www.e-xfl.com/product-detail/intel/epm7256src208-15n</a>

The MAX 7000 architecture supports 100% TTL emulation and high-density integration of SSI, MSI, and LSI logic functions. The MAX 7000 architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 7000 devices are available in a wide range of packages, including PLCC, PGA, PQFP, RQFP, and TQFP packages. See [Table 5](#).

**Table 5. MAX 7000 Maximum User I/O Pins** *Note (1)*

Device	44-Pin PLCC	44-Pin PQFP	44-Pin TQFP	68-Pin PLCC	84-Pin PLCC	100-Pin PQFP	100-Pin TQFP	160-Pin PQFP	160-Pin PGA	192-Pin PGA	208-Pin PQFP	208-Pin RQFP
EPM7032	36	36	36									
EPM7032S	36		36									
EPM7064	36		36	52	68	68						
EPM7064S	36		36		68	68						
EPM7096				52	64	76						
EPM7128E					68	84		100				
EPM7128S					68	84	84 (2)	100				
EPM7160E					64	84		104				
EPM7160S					64		84 (2)	104				
EPM7192E								124	124			
EPM7192S								124				
EPM7256E								132 (2)		164		164
EPM7256S											164 (2)	164

**Notes:**

- (1) When the JTAG interface in MAX 7000S devices is used for either boundary-scan testing or for ISP, four I/O pins become JTAG pins.
- (2) Perform a complete thermal analysis before committing a design to this device package. For more information, see the [Operating Requirements for Altera Devices Data Sheet](#).

MAX 7000 devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000 architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

The MAX 7000 architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. Figure 1 shows the architecture of EPM7032, EPM7064, and EPM7096 devices.

**Figure 1. EPM7032, EPM7064 & EPM7096 Device Block Diagram**

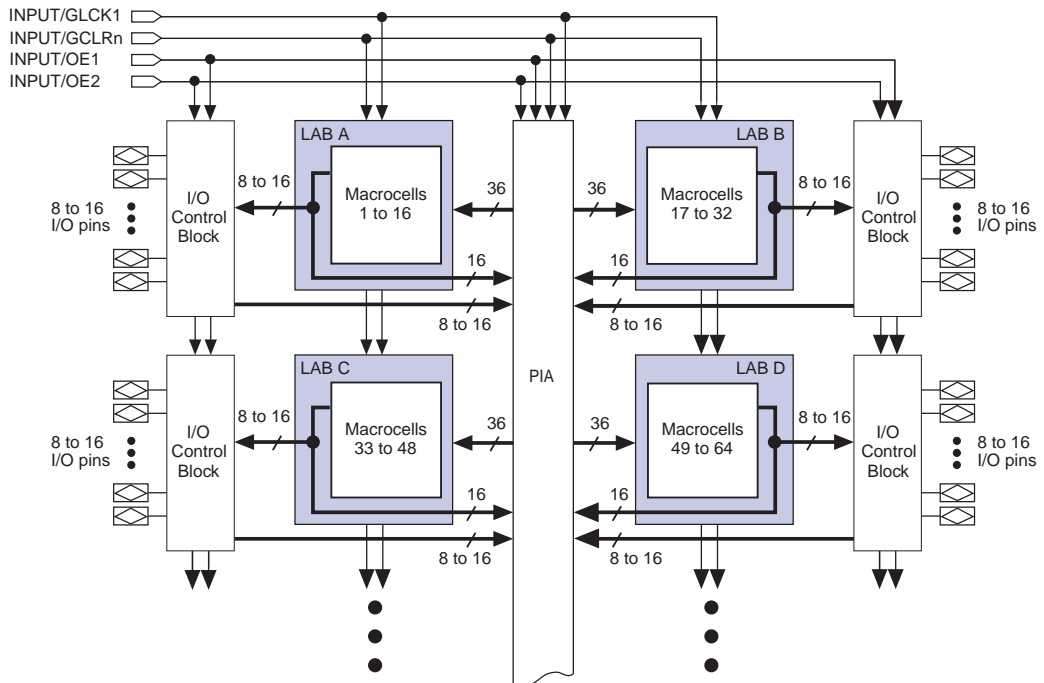
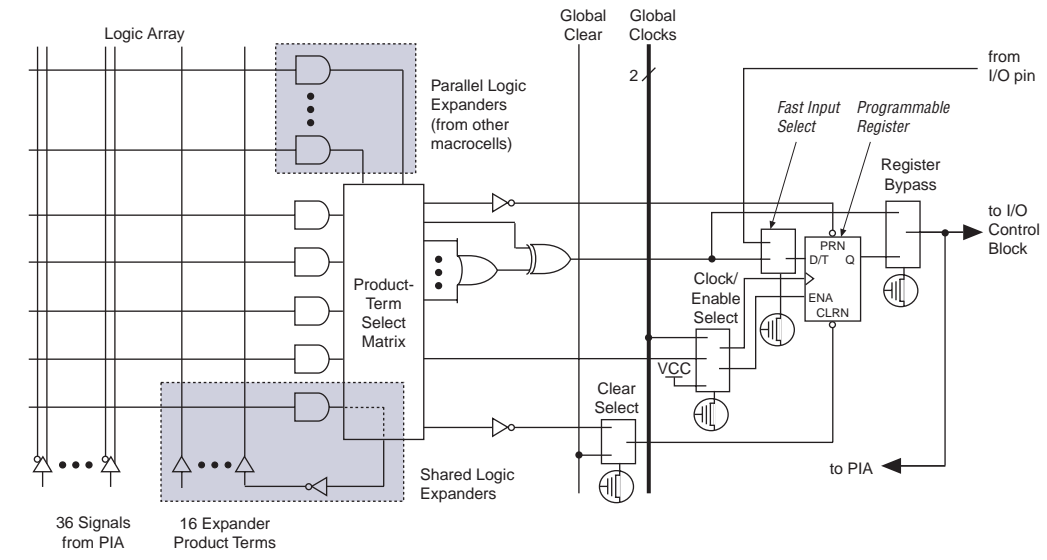


Figure 4 shows a MAX 7000E and MAX 7000S device macrocell.

**Figure 4. MAX 7000E & MAX 7000S Device Macrocell**



Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register clear, preset, clock, and clock enable control functions. Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product-term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera development software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- By a global clock signal. This mode achieves the fastest clock-to-output performance.
- By a global clock signal and enabled by an active-high clock enable. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- By an array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

In EPM7032, EPM7064, and EPM7096 devices, the global clock signal is available from a dedicated clock pin, GCLK1, as shown in [Figure 1](#). In MAX 7000E and MAX 7000S devices, two global clock signals are available. As shown in [Figure 2](#), these global clock signals can be the true or the complement of either of the global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in [Figures 3 and 4](#), the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear of the register are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active-low dedicated global clear pin (GCLRn). Upon power-up, each register in the device will be set to a low state.

All MAX 7000E and MAX 7000S I/O pins have a fast input path to a macrocell register. This dedicated path allows a signal to bypass the PIA and combinatorial logic and be driven to an input D flipflop with an extremely fast (2.5 ns) input setup time.

## Expander Product Terms

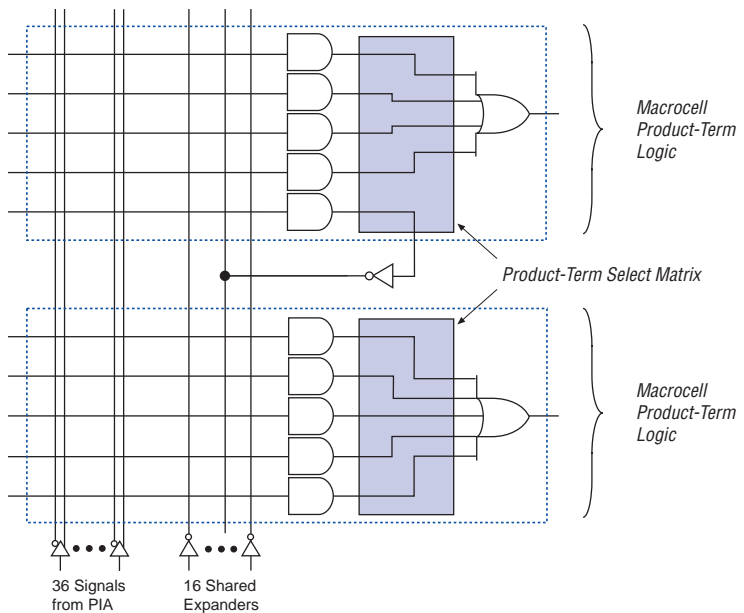
Although most logic functions can be implemented with the five product terms available in each macrocell, the more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources; however, the MAX 7000 architecture also allows both shareable and parallel expander product terms (“expanders”) that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

### Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 5 shows how shareable expanders can feed multiple macrocells.

**Figure 5. Shareable Expanders**

Shareable expanders can be shared by any or all macrocells in an LAB.



### Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

## Programmable Speed/Power Control

MAX 7000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000 device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ , and  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters.

## Output Configuration

MAX 7000 device outputs can be programmed to meet a variety of system-level requirements.

### MultiVolt I/O Interface

MAX 7000 devices—except 44-pin devices—support the MultiVolt I/O interface feature, which allows MAX 7000 devices to interface with systems that have differing supply voltages. The 5.0-V devices in all packages can be set for 3.3-V or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCINT pins must always be connected to a 5.0-V power supply. With a 5.0-V VCCINT level, input voltage thresholds are at TTL levels, and are therefore compatible with both 3.3-V and 5.0-V inputs.

The VCCIO pins can be connected to either a 3.3-V or a 5.0-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 5.0-V supply, the output levels are compatible with 5.0-V systems. When VCCIO is connected to a 3.3-V supply, the output high is 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with VCCIO levels lower than 4.75 V incur a nominally greater timing delay of  $t_{OD2}$  instead of  $t_{OD1}$ .

### Open-Drain Output Option (MAX 7000S Devices Only)

MAX 7000S devices provide an optional open-drain (functionally equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

## Design Security

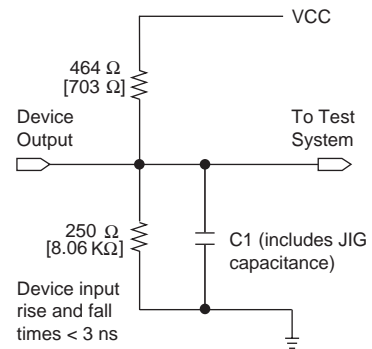
All MAX 7000 devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

## Generic Testing

Each MAX 7000 device is functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in [Figure 10](#). Test patterns can be used and then erased during early stages of the production flow.

**Figure 10. MAX 7000 AC Test Conditions**

*Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V devices and outputs. Numbers without brackets are for 3.3-V devices and outputs.*



## QFP Carrier & Development Socket

MAX 7000 and MAX 7000E devices in QFP packages with 100 or more pins are shipped in special plastic carriers to protect the QFP leads. The carrier is used with a prototype development socket and special programming hardware available from Altera. This carrier technology makes it possible to program, test, erase, and reprogram a device without exposing the leads to mechanical stress.

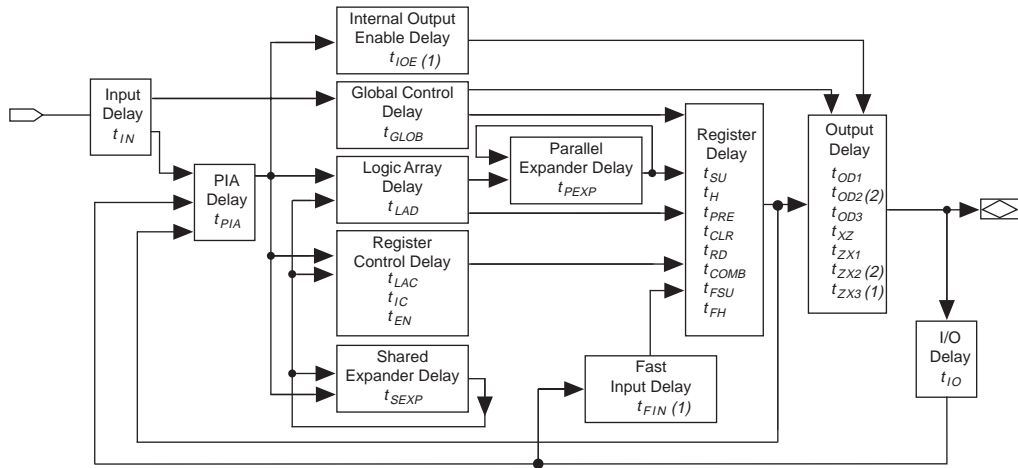


For detailed information and carrier dimensions, refer to the [QFP Carrier & Development Socket Data Sheet](#).



MAX 7000S devices are not shipped in carriers.



**Figure 12. MAX 7000 Timing Model****Notes:**

- (1) Only available in MAX 7000E and MAX 7000S devices.
- (2) Not available in 44-pin devices.

The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 13 shows the internal timing relationship of internal and external delay parameters.



For more information, see [Application Note 94 \(Understanding MAX 7000 Timing\)](#).

Tables 19 through 26 show the MAX 7000 and MAX 7000E AC operating conditions.

**Table 19. MAX 7000 & MAX 7000E External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	-6 Speed Grade		-7 Speed Grade		Unit
			Min	Max	Min	Max	
$t_{PD1}$	Input to non-registered output	C1 = 35 pF		6.0		7.5	ns
$t_{PD2}$	I/O input to non-registered output	C1 = 35 pF		6.0		7.5	ns
$t_{SU}$	Global clock setup time		5.0		6.0		ns
$t_H$	Global clock hold time		0.0		0.0		ns
$t_{FSU}$	Global clock setup time of fast input	(2)	2.5		3.0		ns
$t_{FH}$	Global clock hold time of fast input	(2)	0.5		0.5		ns
$t_{CO1}$	Global clock to output delay	C1 = 35 pF		4.0		4.5	ns
$t_{CH}$	Global clock high time		2.5		3.0		ns
$t_{CL}$	Global clock low time		2.5		3.0		ns
$t_{ASU}$	Array clock setup time		2.5		3.0		ns
$t_{AH}$	Array clock hold time		2.0		2.0		ns
$t_{ACO1}$	Array clock to output delay	C1 = 35 pF		6.5		7.5	ns
$t_{ACH}$	Array clock high time		3.0		3.0		ns
$t_{ACL}$	Array clock low time		3.0		3.0		ns
$t_{CPPW}$	Minimum pulse width for clear and preset	(3)	3.0		3.0		ns
$t_{ODH}$	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
$t_{CNT}$	Minimum global clock period			6.6		8.0	ns
$f_{CNT}$	Maximum internal global clock frequency	(5)	151.5		125.0		MHz
$t_{ACNT}$	Minimum array clock period			6.6		8.0	ns
$f_{ACNT}$	Maximum internal array clock frequency	(5)	151.5		125.0		MHz
$f_{MAX}$	Maximum clock frequency	(6)	200		166.7		MHz

**Table 22. MAX 7000 & MAX 7000E Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			MAX 7000E (-10P)		MAX 7000 (-10) MAX 7000E (-10)		
			Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.5		1.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.5		1.0	ns
$t_{FIN}$	Fast input delay	(2)		1.0		1.0	ns
$t_{SEXP}$	Shared expander delay			5.0		5.0	ns
$t_{PEXP}$	Parallel expander delay			0.8		0.8	ns
$t_{LAD}$	Logic array delay			5.0		5.0	ns
$t_{LAC}$	Logic control array delay			5.0		5.0	ns
$t_{IOE}$	Internal output enable delay	(2)		2.0		2.0	ns
$t_{OD1}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 5.0$ V	$C1 = 35$ pF		1.5		2.0	ns
$t_{OD2}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 3.3$ V	$C1 = 35$ pF (7)		2.0		2.5	ns
$t_{OD3}$	Output buffer and pad delay Slow slew rate = on $V_{CCIO} = 5.0$ V or 3.3 V	$C1 = 35$ pF (2)		5.5		6.0	ns
$t_{ZX1}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 5.0$ V	$C1 = 35$ pF		5.0		5.0	ns
$t_{ZX2}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 3.3$ V	$C1 = 35$ pF (7)		5.5		5.5	ns
$t_{ZX3}$	Output buffer enable delay Slow slew rate = on $V_{CCIO} = 5.0$ V or 3.3 V	$C1 = 35$ pF (2)		9.0		9.0	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5$ pF		5.0		5.0	ns
$t_{SU}$	Register setup time		2.0		3.0		ns
$t_H$	Register hold time		3.0		3.0		ns
$t_{FSU}$	Register setup time of fast input	(2)	3.0		3.0		ns
$t_{FH}$	Register hold time of fast input	(2)	0.5		0.5		ns
$t_{RD}$	Register delay			2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			2.0		1.0	ns
$t_{IC}$	Array clock delay			5.0		5.0	ns
$t_{EN}$	Register enable time			5.0		5.0	ns
$t_{GLOB}$	Global control delay			1.0		1.0	ns
$t_{PRE}$	Register preset time			3.0		3.0	ns
$t_{CLR}$	Register clear time			3.0		3.0	ns
$t_{PIA}$	PIA delay			1.0		1.0	ns
$t_{LPA}$	Low-power adder	(8)		11.0		11.0	ns

**Table 23. MAX 7000 & MAX 7000E External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			MAX 7000E (-12P)		MAX 7000 (-12) MAX 7000E (-12)		
			Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t <sub>SU</sub>	Global clock setup time		7.0		10.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		6.0		6.0	ns
t <sub>CH</sub>	Global clock high time		4.0		4.0		ns
t <sub>CL</sub>	Global clock low time		4.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		3.0		4.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		12.0		12.0	ns
t <sub>ACH</sub>	Array clock high time		5.0		5.0		ns
t <sub>ACL</sub>	Array clock low time		5.0		5.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	5.0		5.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			11.0		11.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	90.9		90.9		MHz
t <sub>ACNT</sub>	Minimum array clock period			11.0		11.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	90.9		90.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	125.0		125.0		MHz

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This parameter applies to MAX 7000E devices only.
- (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (4) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (5) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (6) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (7) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

Tables 27 and 28 show the EPM7032S AC operating conditions.

Table 27. EPM7032S External Timing Parameters (Part 1 of 2)      Note (1)											
Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time		2.9		4.0		5.0		7.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		2.5		2.5		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		0.5		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		3.2		3.5		4.3		5.0	ns
t <sub>CH</sub>	Global clock high time		2.0		2.5		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		2.5		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		0.7		0.9		1.1		2.0		ns
t <sub>AH</sub>	Array clock hold time		1.8		2.1		2.7		3.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		5.4		6.6		8.2		10.0	ns
t <sub>ACH</sub>	Array clock high time		2.5		2.5		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.5		2.5		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			5.7		7.0		8.6		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	175.4		142.9		116.3		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			5.7		7.0		8.6		10.0	ns

**Table 35. EPM7192S External Timing Parameters (Part 2 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
t <sub>AH</sub>	Array clock hold time		1.8		3.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		7.8		10.0		15.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		4.0		6.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		4.0		6.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	3.0		4.0		6.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			8.0		10.0		13.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	125.0		100.0		76.9		MHz
t <sub>ACNT</sub>	Minimum array clock period			8.0		10.0		13.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(4)	125.0		100.0		76.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	166.7		125.0		100.0		MHz

**Table 36. EPM7192S Internal Timing Parameters (Part 1 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		2.0	ns
$t_{FIN}$	Fast input delay			3.2		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			4.2		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.2		0.8		1.0	ns
$t_{LAD}$	Logic array delay			3.1		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			3.1		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.9		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		7.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.1		2.0		4.0		ns

**Table 38. EPM7256S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		2.0	ns
$t_{FIN}$	Fast input delay			3.4		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			3.9		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.1		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.6		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			2.6		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.8		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.1		2.0		4.0		ns
$t_H$	Register hold time		1.6		3.0		4.0		ns
$t_{FSU}$	Register setup time of fast input		2.4		3.0		2.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.5		1.0		ns
$t_{RD}$	Register delay			1.1		2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.1		2.0		1.0	ns
$t_{IC}$	Array clock delay			2.9		5.0		6.0	ns
$t_{EN}$	Register enable time			2.6		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.8		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.7		3.0		4.0	ns
$t_{CLR}$	Register clear time			2.7		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		3.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		10.0		11.0		13.0	ns

**Table 39. MAX 7000  $I_{CC}$  Equation Constants**

Device	A	B	C
EPM7032	1.87	0.52	0.144
EPM7064	1.63	0.74	0.144
EPM7096	1.63	0.74	0.144
EPM7128E	1.17	0.54	0.096
EPM7160E	1.17	0.54	0.096
EPM7192E	1.17	0.54	0.096
EPM7256E	1.17	0.54	0.096
EPM7032S	0.93	0.40	0.040
EPM7064S	0.93	0.40	0.040
EPM7128S	0.93	0.40	0.040
EPM7160S	0.93	0.40	0.040
EPM7192S	0.93	0.40	0.040
EPM7256S	0.93	0.40	0.040

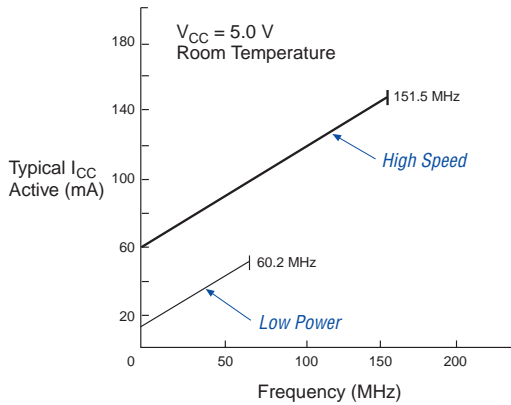
This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  values should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.



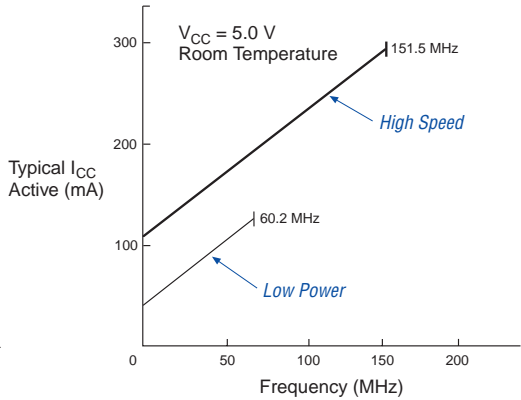
Figure 14 shows typical supply current versus frequency for MAX 7000 devices.

Figure 14.  $I_{CC}$  vs. Frequency for MAX 7000 Devices (Part 1 of 2)

EPM7032



EPM7064



EPM7096

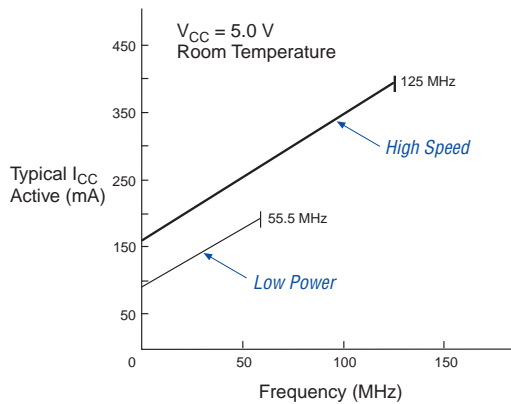
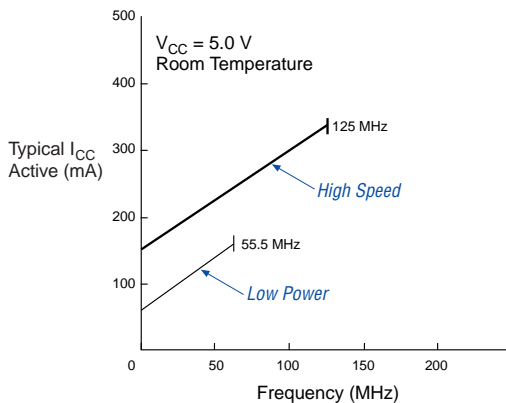
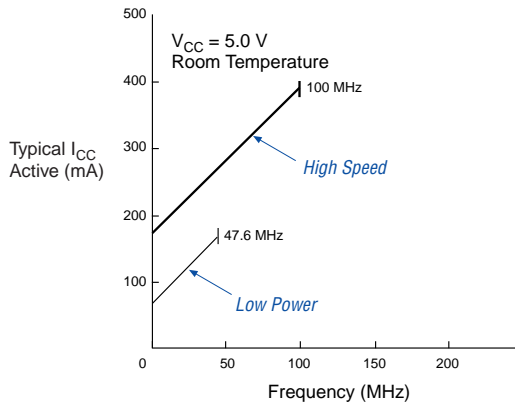


Figure 14.  $I_{CC}$  vs. Frequency for MAX 7000 Devices (Part 2 of 2)

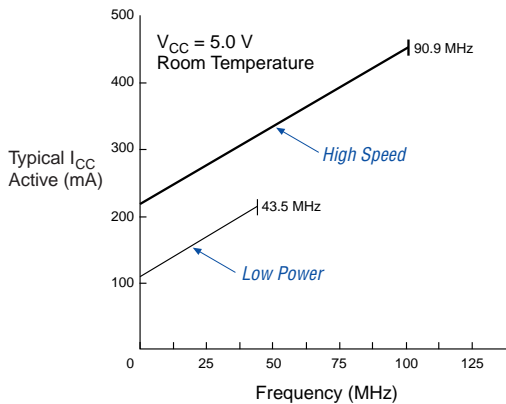
EPM7128E



EPM7160E



EPM7192E



EPM7256E

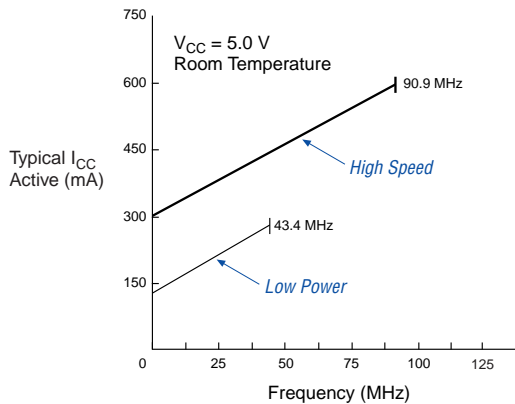
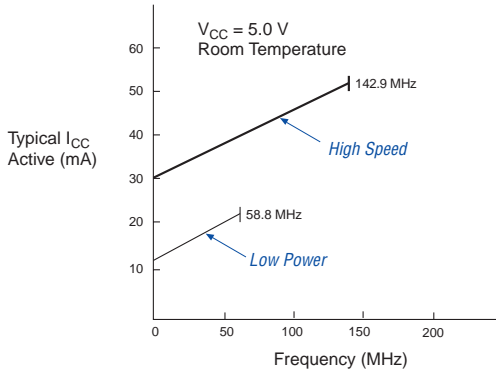


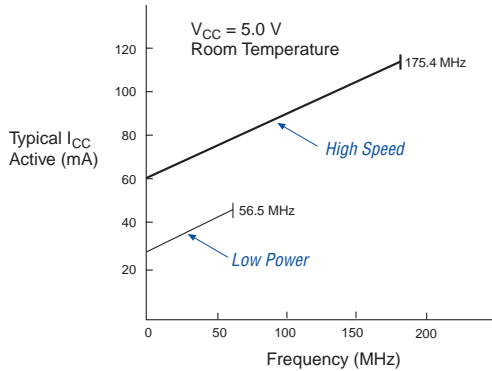
Figure 15 shows typical supply current versus frequency for MAX 7000S devices.

**Figure 15.  $I_{CC}$  vs. Frequency for MAX 7000S Devices (Part 1 of 2)**

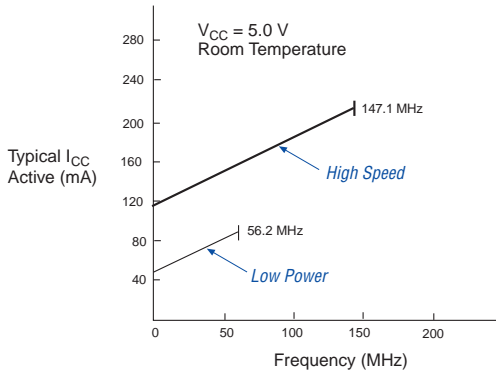
**EPM7032S**



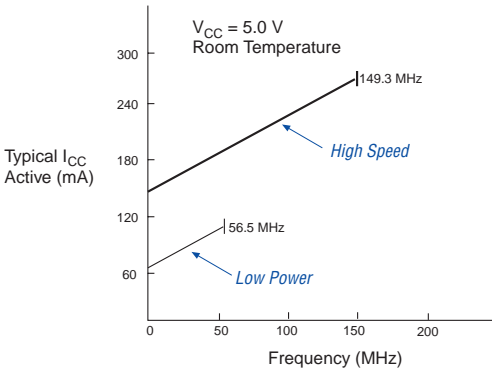
**EPM7064S**



**EPM7128S**

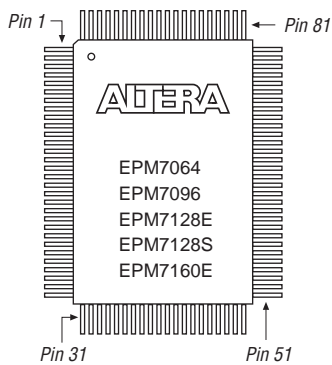


**EPM7160S**

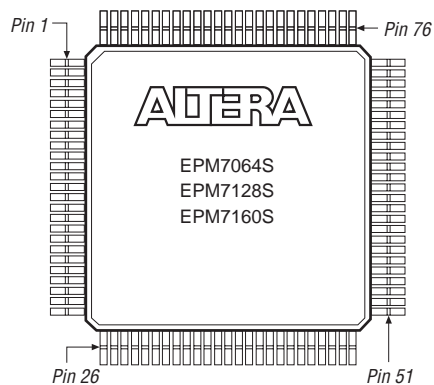


**Figure 19. 100-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.



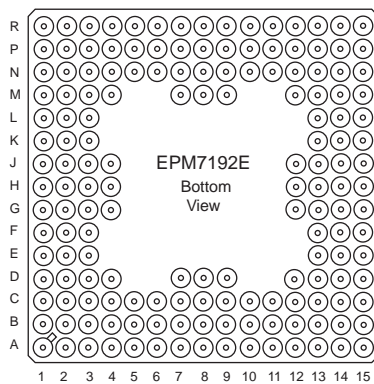
100-Pin PQFP



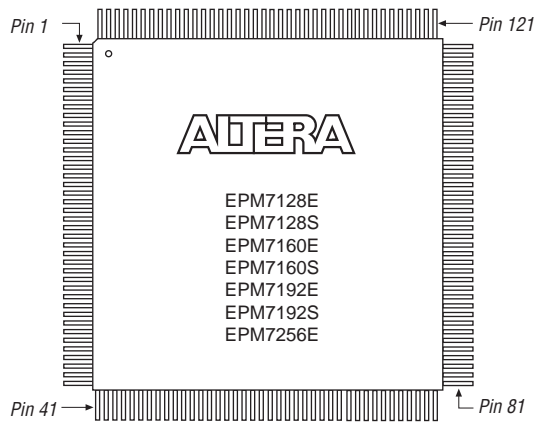
100-Pin TQFP

**Figure 20. 160-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.



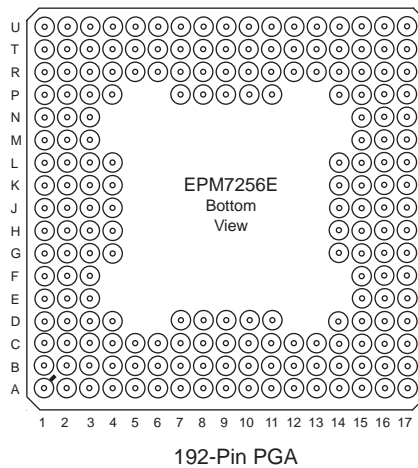
160-Pin PGA



160-Pin PQFP

**Figure 21. 192-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.

**Figure 22. 208-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.

